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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10047454	01/14/2002	250	234	2878	Luu

**APPLICANTS: Kley Victor;

**CONTINUING DATA VERIFIED:

THIS APPLICATION IS A CON OF 08/776,361 05/16/1997 PAT 6,339,217 JRL 2501216
WHICH IS A 371 OF PCT/US95/09553 07/28/1995
WHICH IS A CIP OF 08/412,380 03/29/1995 ABN
WHICH IS A CIP OF 08/281,883 07/28/1994 ABN

** FOREIGN APPLICATIONS VERIFIED:

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed 35 USC 119 conditions met Verified and Acknowledged Examiners's initials		<input type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO 020921-001110US
TITLE : Scanning probe microscope assembly			
U.S. DEPT. OF COMM./PAT. & TM-PTO-436L(Rev. 12-94)			

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G
		DRAWING	
		Sheets Drwg.	Figs.Drwg.
		Print Fig.	
		Primary Examiner	
		PREPARED FOR ISSUE	
		Application Examiner	
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